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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/706,531	BASEMAN ET AL.	
Examiner	Art Unit	
Paul D. Kim	3729	

	SEARCHED					
Class	Subclass	Date		Examiner		
29	603.07 603.13- 603.16 603.18	3/17/200)6	PK		
216	22,48 65					
360	316 324.1					
	324.11					
	324.12					
427	127 128					
451	5,41					
360	324.2	V				

INT	INTERFERENCE SEARCHED				
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	DATE	EXMR
Text Search EAST/NPL (IEEE)	3/17/2006	PK
Updated Text Search EAST/PGPub	6/6/2006	PK